

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/893,874 KOBAYASHI ET AL.	
		Examiner	Art Unit	Page 1 of 3 Ayal I Sharon 2123

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,852,560	12-1998	Takeyama et al.	700/97
	B	US-6,811,344	11-2004	Kobayashi et al.	403/2
	C	US-2001/0029461	10-2001	Kobayashi, Hideki	705/8
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 01/59640 A2	08-2001	WIPO	Matsuda, M.	G06F 17/60
	O	JP 11025064	09-1999	Japan	Shibata Miyuki	G06F 17/60
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zhou, Mengchu et al., "Evaluation of Environmentally Conscious Product Designs". 1998 IEEE Int'l Conf. on Systems, Man, and Cybernetics. Oct. 1998. vol.4, pp.4057-4061.
	V	Anderi, R. et al. "Design for Environment - A Computer-Based Cooperative Method to Consider the Entire Life Cycle." Proc. EcoDesign '99: 1st Int'l Symposium on Environmentally Conscious Design and Inverse Manuf. Feb. 1999. pp.380-385.
	W	Zhou, Mengchu et al., "A Cost Model for Multi-Lifecycle Engineering Design". IEEE Conf. on Emerging Technologies and Factory Automation (EFTA '96). Nov. 1996. Vol.1. pp.385-391.
	X	Hoshino, T. et al. "Optimization Analysis for Recycle-Oriented Manufacturing Systems". Int. Journal Production Research. 1995. vol.33, No.8, pp.2069-2078.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL.	
		Examiner Ayal I Sharon	Art Unit 2123	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dalke, D. et al. "Product Environmental Impact Assessments". 1994 IEEE Int'l Symposium on Electronics and the Environment. May 1994. pp.187-190.
	V	Luo, Yanchun et al. "Lifecycle Analysis for Environmentally Conscious Solid Freeform Manufacturing." Proc. of the 2000 IEEE Int'l Symposium on Electronics and the Environment. May 2000. pp.33-38.
	W	Grenchus, E. "Composition and Value of Returned Consumer and Industrial Information Technology Equipment." Proc. of the 2000 IEEE Int'l Symposium on Electronics and the Environment. May 2000. pp.324-329.
	X	Yan, Pingtao et al. "Multi-Lifecycle Product and Process Development: Selection of Optimal Production, Usage, and Recovery Processes." Proc. of the 1999 Int'l Symposium on Electronics and the Environment. May 1999. pp.274-279.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL.	
		Examiner Ayal I Sharon	Art Unit 2123	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Limaye, K. et al. "System Simulation and Modeling of Electronics Demanufacturing Facilities." Proc. 1999 IEEE Int'l Symposium on Electronics and the Environment. May 1999. pp.238-243.
	V	Thomas, V. et al. "Information Technology and Product Lifecycle." Proc. 1999 IEEE Int'l Symposium on Electronics and the Environment. May 1999. pp.54-57.
	W	European Patent Office Int'l Search Report for Related U.S. Application 10/323,792 and European Application EP 02 25 8945.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.